



IAUC70N08S5N074

OptiMOS™-5 Power-Transistor



Features

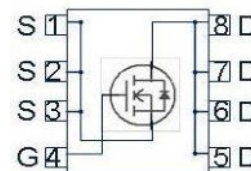
- N-channel - Enhancement mode
- AEC Q101 qualified
- MSL1 up to 260°C peak reflow
- 175°C operating temperature
- Green product (RoHS compliant)
- 100% Avalanche tested

Product Summary

V_{DS}	80	V
$R_{DS(on)}$	7.4	mΩ
I_D	70	A



Type	Package	Marking
IAUC70N08S5N074	PG-TDSON-8	5N08074



Maximum ratings, at $T_J=25\text{ °C}$, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I_D	$T_C=25\text{ °C}$, $V_{GS}=10\text{ V}$	70	A
		$T_C=100\text{ °C}$, $V_{GS}=10\text{ V}^{1)}$	47	
Pulsed drain current ¹⁾	$I_{D,pulse}$	$T_C=25\text{ °C}$	280	
Avalanche energy, single pulse ¹⁾	E_{AS}	$I_D=35\text{ A}$	57	mJ
Avalanche current, single pulse	I_{AS}	-	70	A
Gate source voltage	V_{GS}	-	±20	V
Power dissipation	P_{tot}	$T_C=25\text{ °C}$	83	W
Operating and storage temperature	T_J , T_{stg}	-	-55 ... +175	°C
IEC climatic category; DIN IEC 68-1	-	-	55/175/56	

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	

Thermal characteristics¹⁾

Thermal resistance, junction - case	R_{thJC}	-	-	-	1.8	K/W
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Electrical characteristics, at $T_j=25\text{ °C}$, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	$V_{(BR)DSS}$	$V_{GS}=0\text{ V}$, $I_D=1\text{ mA}$	80	-	-	V
Gate threshold voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}$, $I_D=36\text{ }\mu\text{A}$	2.2	3	3.8	
Zero gate voltage drain current	I_{DSS}	$V_{DS}=80\text{ V}$, $V_{GS}=0\text{ V}$, $T_j=25\text{ °C}$	-	0.1	1	μA
		$V_{DS}=80\text{ V}$, $V_{GS}=0\text{ V}$, $T_j=85\text{ °C}^{1)}$	-	1	20	
Gate-source leakage current	I_{GSS}	$V_{GS}=20\text{ V}$, $V_{DS}=0\text{ V}$	-	-	100	nA
Drain-source on-state resistance	$R_{DS(on)}$	$V_{GS}=6\text{ V}$, $I_D=18\text{ A}$	-	9.1	10.6	$\text{m}\Omega$
		$V_{GS}=10\text{ V}$, $I_D=35\text{ A}$	-	6.6	7.4	
Gate resistance ¹⁾	R_G		-	1.2	-	Ω



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Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	

Dynamic characteristics¹⁾

Input capacitance	C_{iss}	$V_{GS}=0\text{ V}, V_{DS}=40\text{ V},$ $f=1\text{ MHz}$	-	1600	2080	pF
Output capacitance	C_{oss}		-	274	356	
Reverse transfer capacitance	C_{rss}		-	14	22	
Turn-on delay time	$t_{d(on)}$	$V_{DD}=40\text{ V}, V_{GS}=10\text{ V},$ $I_D=70\text{ A}, R_G=3.5\ \Omega$	-	4.7	-	ns
Rise time	t_r		-	1.2	-	
Turn-off delay time	$t_{d(off)}$		-	7	-	
Fall time	t_f		-	5.8	-	

Gate Charge Characteristics¹⁾

Gate to source charge	Q_{gs}	$V_{DD}=40\text{ V}, I_D=35\text{ A},$ $V_{GS}=0\text{ to }10\text{ V}$	-	8.0	10.0	nC
Gate to drain charge	Q_{gd}		-	5.2	8.0	
Gate charge total	Q_g		-	23.0	30.0	
Gate plateau voltage	$V_{plateau}$		-	4.9	-	V

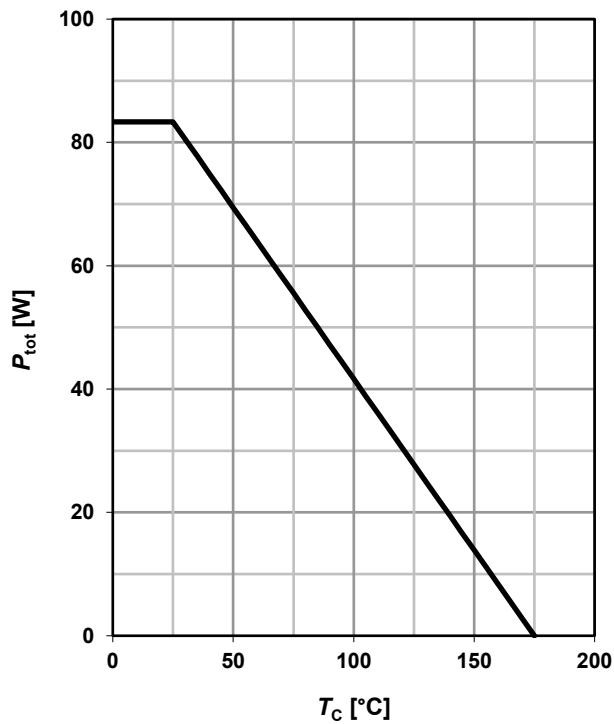
Reverse Diode

Diode continuous forward current ¹⁾	I_S	$T_C=25\text{ °C}$	-	-	70	A
Diode pulse current ¹⁾	$I_{S,pulse}$		-	-	280	
Diode forward voltage	V_{SD}	$V_{GS}=0\text{ V}, I_F=35\text{ A},$ $T_J=25\text{ °C}$	-	0.9	1.2	V
Reverse recovery time ¹⁾	t_{rr}	$V_R=40\text{ V}, I_F=50\text{ A},$ $di_F/dt=100\text{ A}/\mu\text{s}$	-	40	-	ns
Reverse recovery charge ¹⁾	Q_{rr}		-	60	-	nC

¹⁾ Defined by design. Not subject to production test.

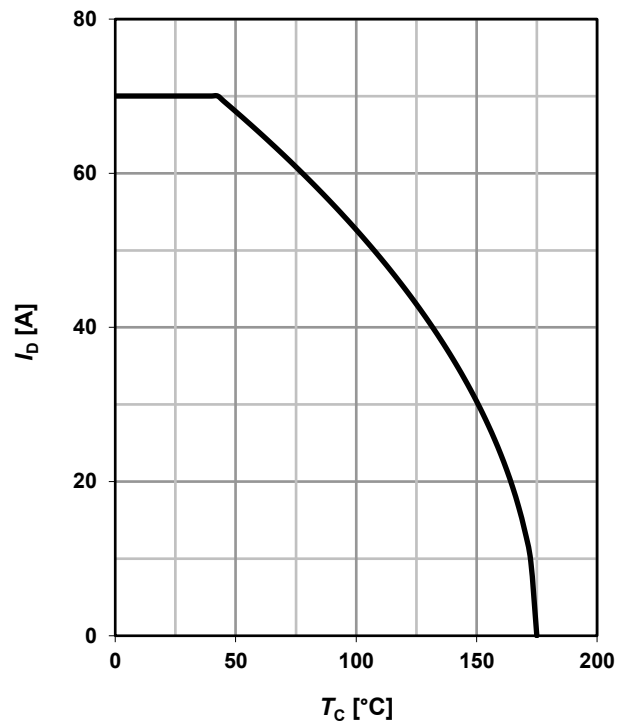
1 Power dissipation

$$P_{\text{tot}} = f(T_C); V_{\text{GS}} \geq 6 \text{ V}$$



2 Drain current

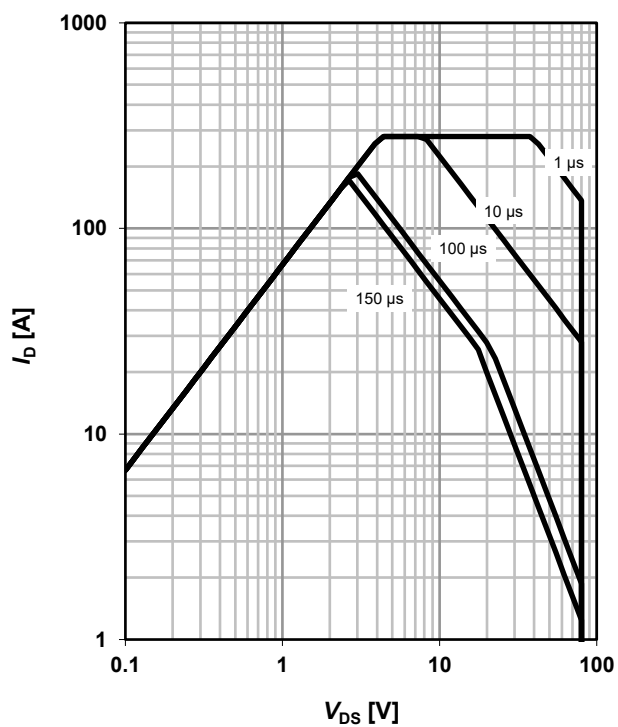
$$I_D = f(T_C); V_{\text{GS}} \geq 6 \text{ V}$$



3 Safe operating area

$$I_D = f(V_{\text{DS}}); T_C = 25 \text{ °C}; D = 0$$

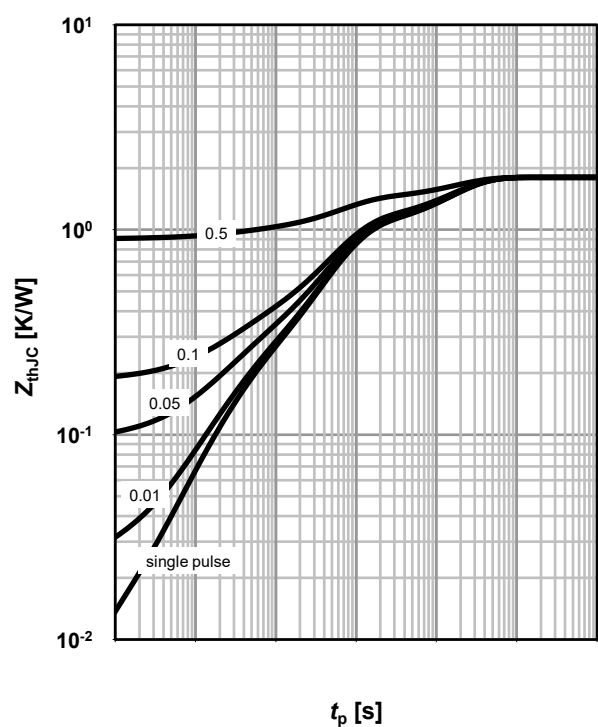
parameter: t_p



4 Max. transient thermal impedance

$$Z_{\text{thJC}} = f(t_p)$$

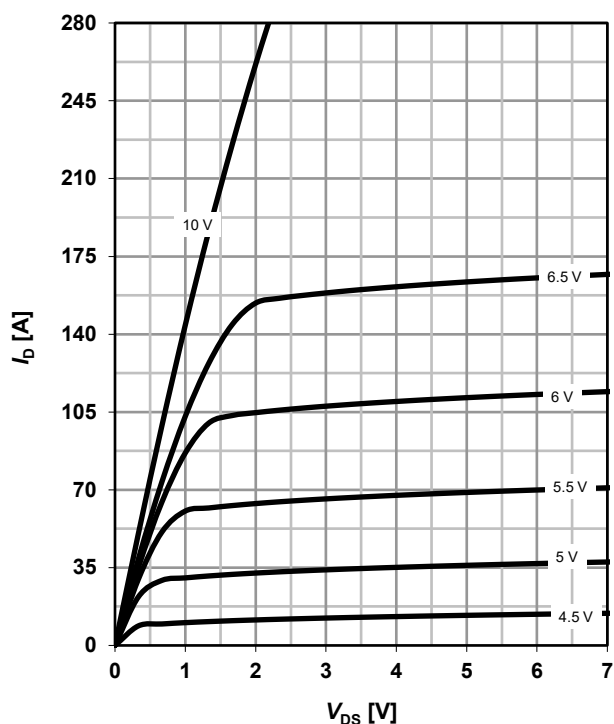
parameter: $D = t_p/T$



5 Typ. output characteristics

$I_D = f(V_{DS}); T_j = 25^\circ\text{C}$

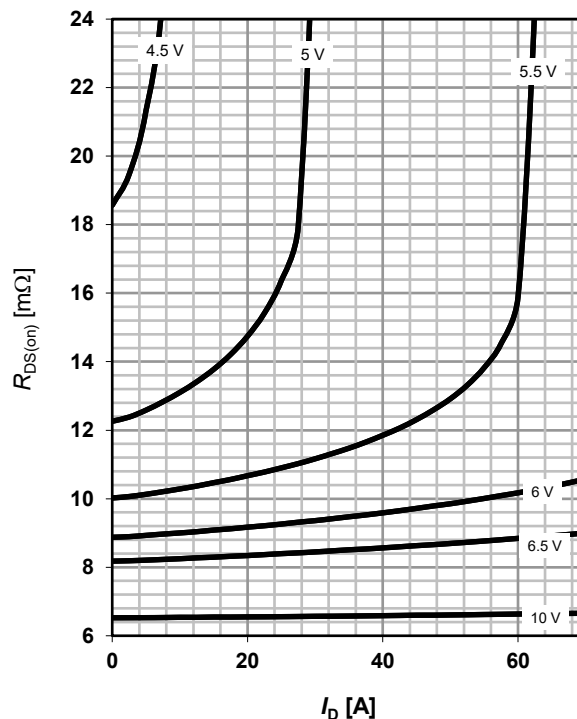
parameter: V_{GS}



6 Typ. drain-source on-state resistance

$R_{DS(on)} = f(I_D); T_j = 25^\circ\text{C}$

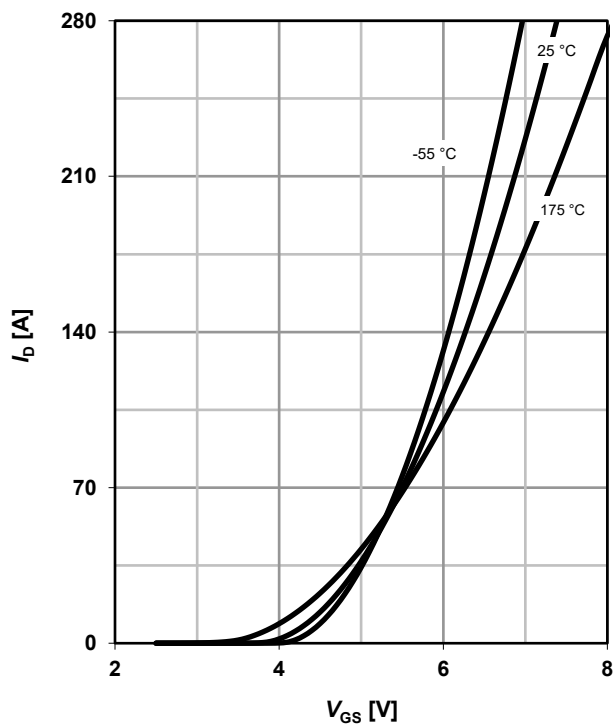
parameter: V_{GS}



7 Typ. transfer characteristics

$I_D = f(V_{GS}); V_{DS} = 6\text{ V}$

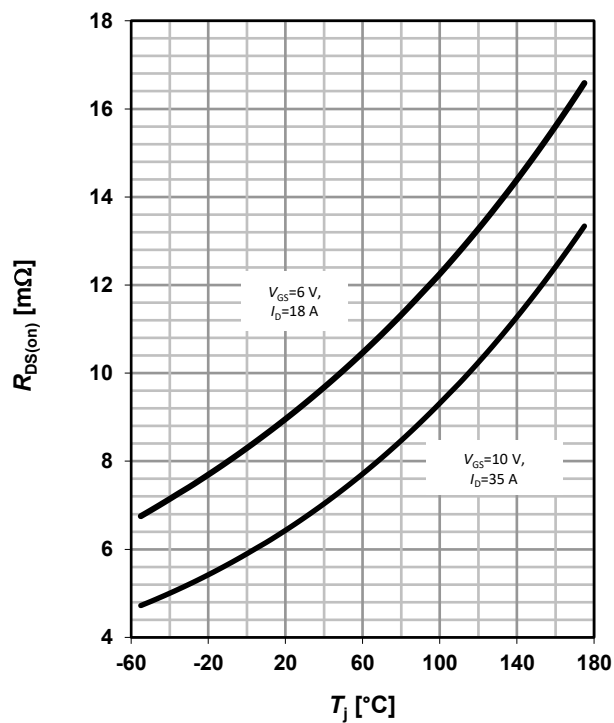
parameter: T_j



8 Typ. drain-source on-state resistance

$R_{DS(on)} = f(T_j)$

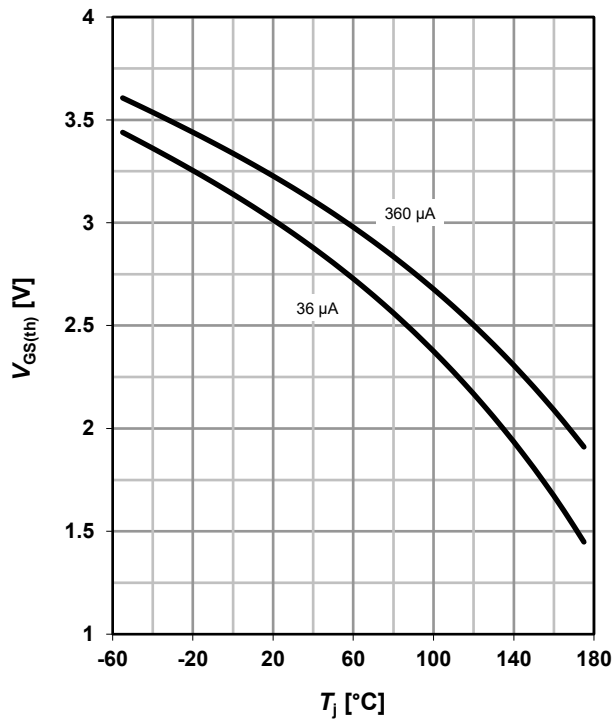
parameter: $V_{GS}; I_D$



9 Typ. gate threshold voltage

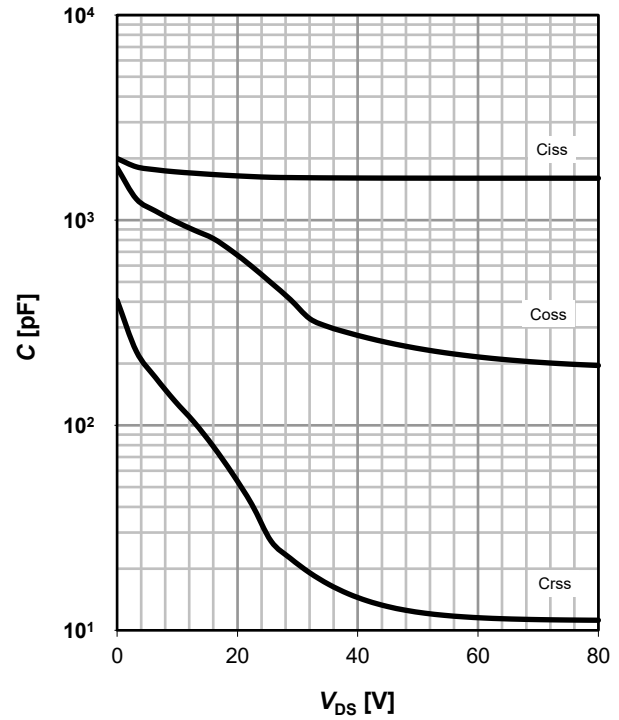
$$V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$$

parameter: I_D



10 Typ. capacitances

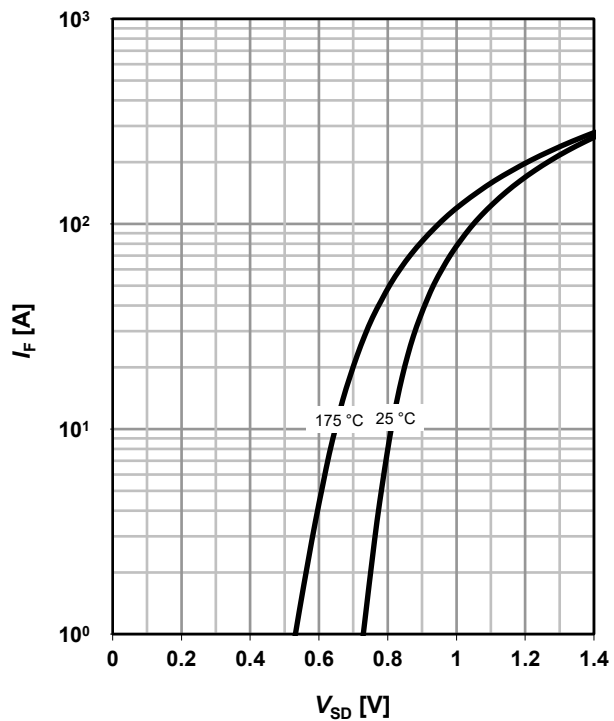
$$C = f(V_{DS}); V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}$$



11 Typical forward diode characteristics

$$I_F = f(V_{SD})$$

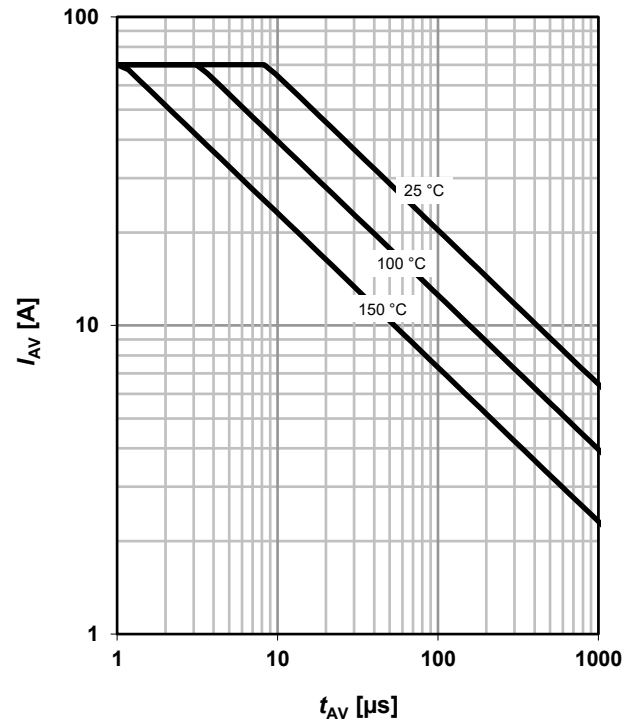
parameter: T_j



12 Typ. avalanche characteristics

$$I_{AS} = f(t_{AV})$$

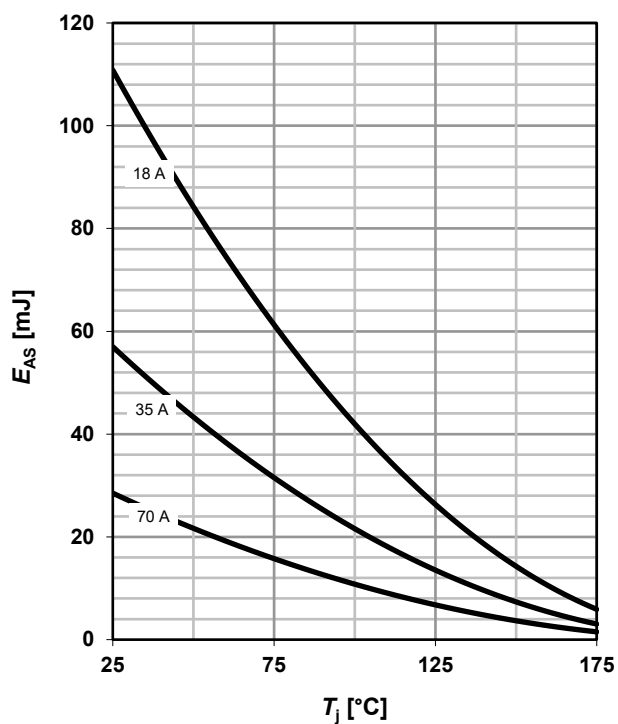
parameter: $T_{j(start)}$



13 Typical avalanche energy

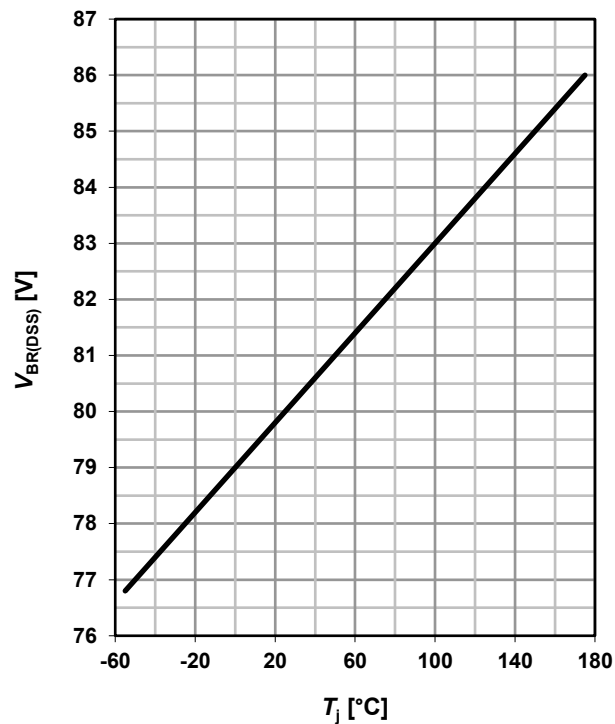
$$E_{AS} = f(T_j)$$

parameter: I_D



14 Drain-source breakdown voltage

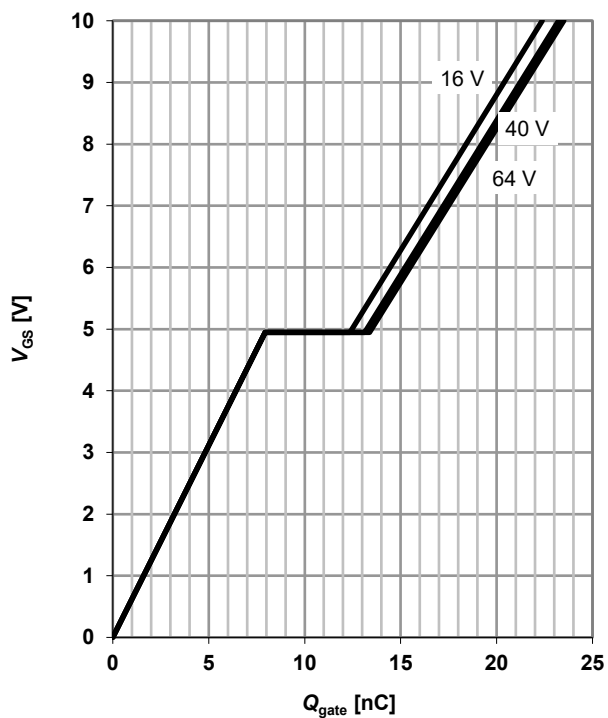
$$V_{BR(DSS)} = f(T_j); I_{D_typ} = 1 \text{ mA}$$



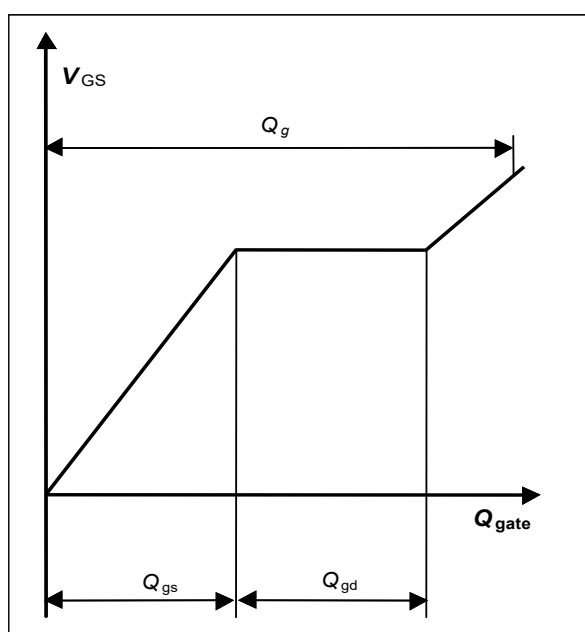
15 Typ. gate charge

$$V_{GS} = f(Q_{gate}); I_D = 35 \text{ A pulsed}$$

parameter: V_{DD}



16 Gate charge waveforms



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Revision History

Version	Date	Changes
Version 1.0	24.07.2018	Final Data Sheet